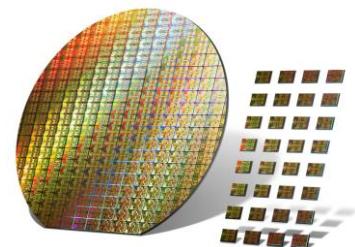


NPT IGBT Chip

| Chip Type | V _{CE} | I _C | Die size |
|-----------|-----------------|----------------|-----------------------------|
| An25IGB12 | 1 200 V | 25 A | 6.59 x 6.49 mm ² |



FEATURES

- 1 200 V NPT technology
- Low turn-off losses
- Short tail current
- Positive temperature coefficient
- Easy paralleling
- High short circuit capability

Recommended for:

- Low power Modules

GENERAL INFORMATION:

| | |
|---|---|
| Die size (including scribe line) | 6.59 x 6.49 mm ² |
| Emitter and Gate pad size | See chip drawing |
| Area total | 42.77 mm ² |
| Scribe line width | 0.1 mm |
| Wafer size | 150 mm (6 inch) |
| Wafer thickness | 200 um |
| Type and thickness of Emitter and Gate metal layer | Al Si 1% 4.0 um |
| Type and thickness of Collector metal layer (wafer back side) | Ti – Ni – Ag 1.0 um |
| Passivation frontside | Polyimide |
| Die bond | Electrically conductive glue or solder |
| Wire bond | Al, ≤ 500 um |
| Recommended storage environment | Store in original container, in dry nitrogen, < 6 month at an ambient temperature 23°C |

MAXIMUM RATINGS:

| Parameter | Legend | Value | Unit |
|--|----------------|------------------|------------------|
| Collector-emitter voltage, $T_J=25\text{ }^\circ\text{C}$ | V_{CE} | 1 200 | V |
| DC collector current, limited by T_{jmax} | I_C | 25 ¹⁾ | A |
| Pulsed collector current, t_p limited by T_{jmax} | $I_{c,puls}$ | 70 | A |
| Gate emitter voltage | V_{GE} | ± 30 | V |
| Operating junction and storage temperature | T_j, T_{stg} | -55 ... +150 | $^\circ\text{C}$ |
| Short circuit data ^{1) 2)} $V_{GE}=15\text{ V}$, $V_{CC}=800\text{ V}$, $T_J=150\text{ }^\circ\text{C}$ | t_{sc} | 10 | us |

STATIC CHARACTERISTICS (tested on wafer), $T_J=25\text{ }^\circ\text{C}$:

| Parameter | Legend | Condition | Value | | | Unit |
|--------------------------------------|---------------|--|-------|-------------------|-------------------|----------|
| | | | min. | typ. | max | |
| Collector-emitter breakdown voltage | $V_{(BR)CES}$ | $V_{GE}=0\text{ V}$, $I_C=1\text{ mA}$ | 1 200 | - | - | V |
| Collector-emitter saturation voltage | $V_{CE(sat)}$ | $V_{GE}=15\text{ V}$, $I_C=20\text{ A}$ | - | 2.35 | 2.5 | |
| | | $V_{GE}=15\text{ V}$, $I_C=25\text{ A}$ | - | 2.4 ³⁾ | 2.8 ³⁾ | |
| Gate-emitter threshold voltage | $V_{GE(th)}$ | $I_C=1\text{ mA}$, $V_{GE}=V_{CE}$ | 3.0 | 4.8 | 6.0 | |
| Zero gate voltage collector current | I_{CES} | $V_{CE}=1\,200\text{ V}$, $V_{GE}=0\text{ V}$ | - | - | 10 | uA |
| Gate-emitter leakage current | I_{GES} | $V_{CE}=0\text{ V}$, $V_{GE}=20\text{ V}$ | - | - | 80 | nA |
| Integrated gate resistor | R_{Gint} | | - | 5 | - | Ω |

ELECTRICAL CHARACTERISTICS (verified by design/ characterization):

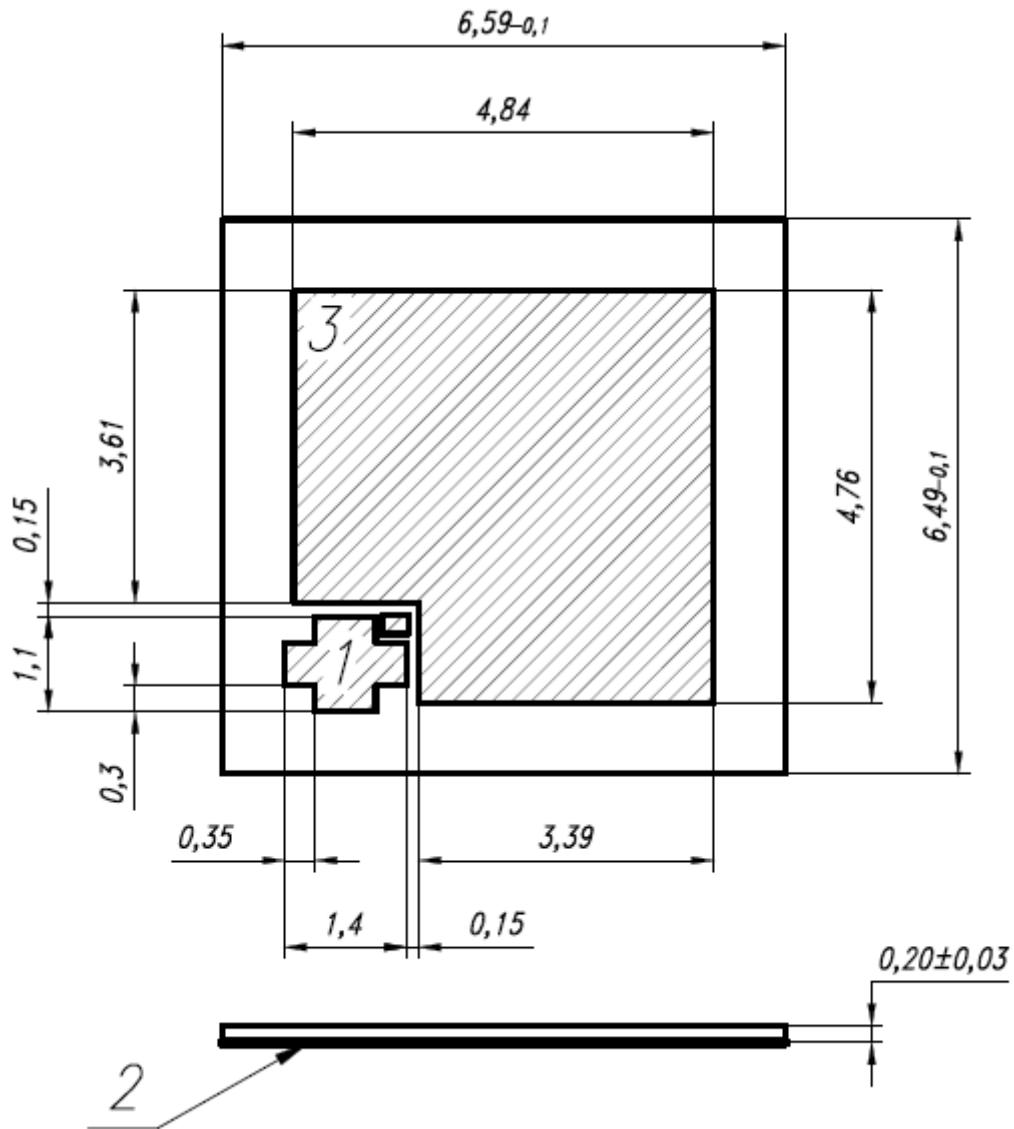
| Parameter | Legend | Condition | Value | | | Unit |
|------------------------------|-----------|---|-------|-------|-----|------|
| | | | min. | typ. | max | |
| Input capacitance | C_{iss} | $V_{CE}=25\text{ V}$, $V_{GE}=0\text{ V}$, $f=1\text{ MHz}$ | - | 1 700 | - | pF |
| Output capacitance | C_{oss} | | - | 220 | - | |
| Reverse transfer capacitance | C_{rss} | | - | 90 | - | |

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

¹⁾ Depending on thermal properties of assembly

²⁾ Not subject to production test – verified by design/characterization

³⁾ Data for chip packaged in power modules

CHIP DRAWING:

NOTE:
ASSIGNMENTS

1 Dimensions are shown in milimeters.

PAD:

1 = GATE

2 = COLLECTOR (BACK SIDE)

3 = Emitter